

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/766,373	ZHOU ET AL.
	Examiner	Art Unit
	Leith A. Al-Nazer	2821

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
372	109	4/20/2005	LA
356	300	4/20/2005	LA
356	326	4/20/2005	LA
356/451		4/20/2005	LA